

WEST

## Freeform Search

**Database:**

- US Patents Full Text Database
- US Pre-Grant Publication Full Text Database
- IPC Abstracts Database
- MIPO Abstracts Database
- Derwent World Patents Index
- USPTO Technical Disclosure Database

**Term:** 115 and (compress\$4 or compact\$4) same (pull\$1up or pull\$1down)same latch\$4 same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing)same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4)

**Display:** 20 Documents in Display Format: - Starting with Number 1

**Generate:**  Hit List  Hit Count  Side by Side  Image

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## Search History

**DATE:** Monday, September 30, 2002 [Printable Copy](#) [Create Case](#)

<u>Set</u> <u>Name</u>	<u>Query</u>	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u>
side by side	DB=USPT,PGPB,JPAB,EPAB,DWPI,TDBD; PLUR=YES; OP=ADJ		result set
L18	115 and 116	4	<u>L18</u>
L17	115 and (compress\$4 or compact\$4) same (pull\$1up or pull\$1down)same latch\$4 same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing)same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4)	4	<u>L17</u>
L16	114 and (compress\$4 or compact\$4) same (pull\$1up or pull\$1down)same latch\$4 same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing)same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4)	4	<u>L16</u>
L15	114 and (compress\$4 or compact\$4) and (pull\$1up or pull\$1down)same latch\$4 same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing)same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4)	43	<u>L15</u>

<u>L14</u>	l13 and (compress\$4 or compact\$4) and (pull\$1up or pull\$1down)same latch\$4 same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing)	115	<u>L14</u>
<u>L13</u>	(compress\$4 or compact\$4) and (pull\$1up or pull\$1down)same latch\$4	498	<u>L13</u>
<u>L12</u>	l1 and (pull\$1up or pull\$1down)same latch\$4	1	<u>L12</u>
<u>L11</u>	l7 and (pull\$1up or pull\$1down)same latch\$4	1	<u>L11</u>
<u>L10</u>	(pull\$1up or pull\$1down)same latch\$4	2589	<u>L10</u>
<u>L9</u>	('6163491')[ABPN1,NRPN,PN,TBAN,WKU]	2	<u>L9</u>
<u>L8</u>	l7 and double data rate same (compress\$4 or compact\$4) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing)	1	<u>L8</u>
<u>L7</u>	l6 and double data rate and (compress\$4 or compact\$4) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing)	11	<u>L7</u>
<u>L6</u>	double data rate and (compress\$4 or compact\$4) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7)	12	<u>L6</u>
<u>L5</u>	l1 and (double near (data or rate) or ddr )same (compress\$4 or compact\$4) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) and (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7)	11	<u>L5</u>
<u>L4</u>	('6324602')[ABPN1,NRPN,PN,TBAN,WKU]	2	<u>L4</u>
<u>L3</u>	('6317372')[ABPN1,NRPN,PN,TBAN,WKU]	2	<u>L3</u>
<u>L2</u>	l1 and (double near (data or rate) or ddr )same (compress\$4 or compact\$4) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7)	3	<u>L2</u>
<u>L1</u>	(double near (data or rate) or ddr )same (compress\$4 or compact\$4)	163	<u>L1</u>

END OF SEARCH HISTORY